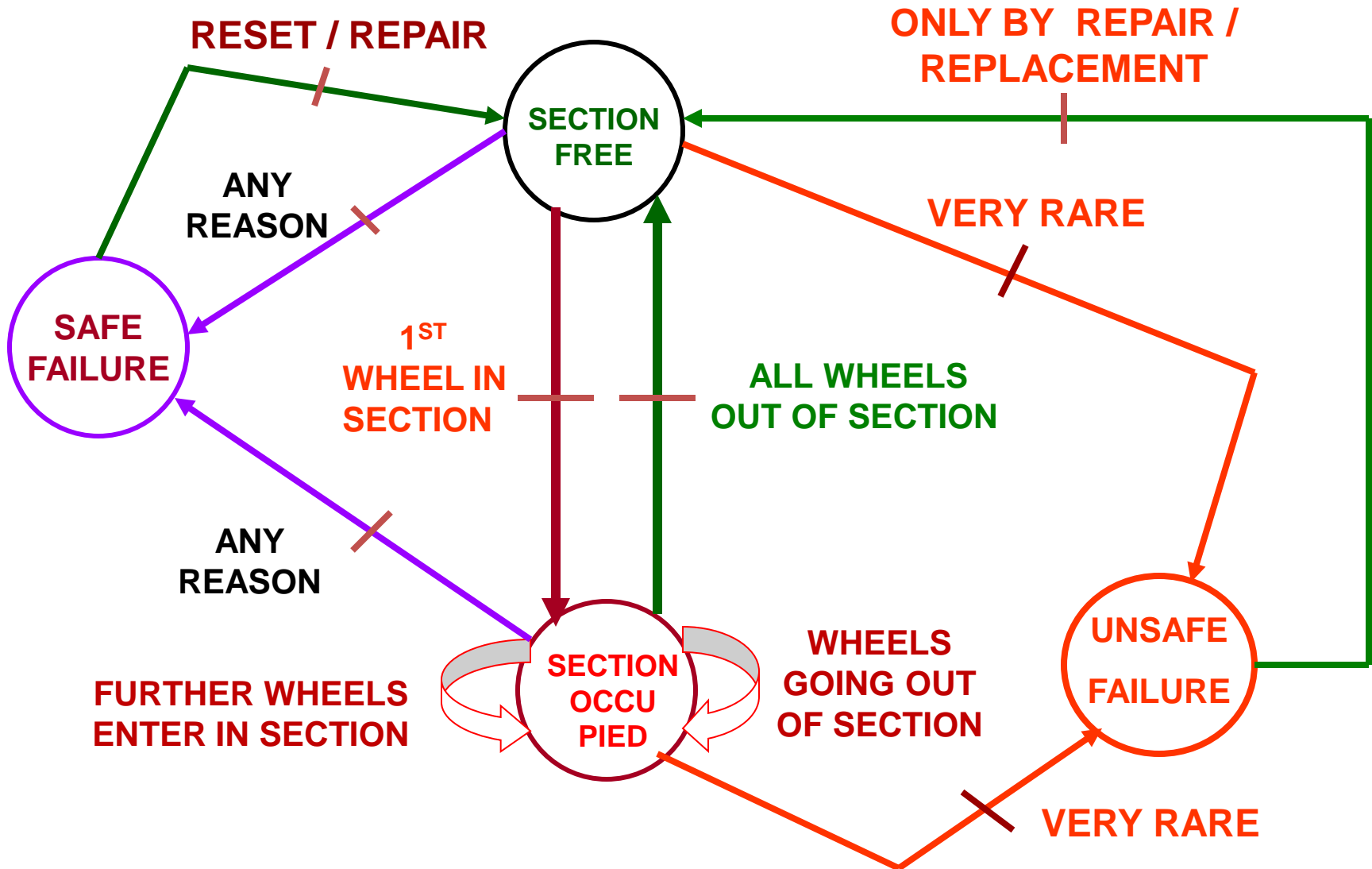




# QUANTITATIVE TECHNIQUES IN SAFETY MANAGEMENT

**SOMNATH PAL** MIRSE, CSTM, CSQP  
Asst. Prof. (Retd) /  
**INDIAN RAILWAYS INSTT. OF**  
**SIGNAL ENGG. & TELECOMMUNICATION**

# RAILWAY SIGNALING CAN BE DEFINED AS A STATE MACHINE.



**SIGNAL FAILURES CAN BE SAFE OR UNSAFE  
(DANGEROUS).**

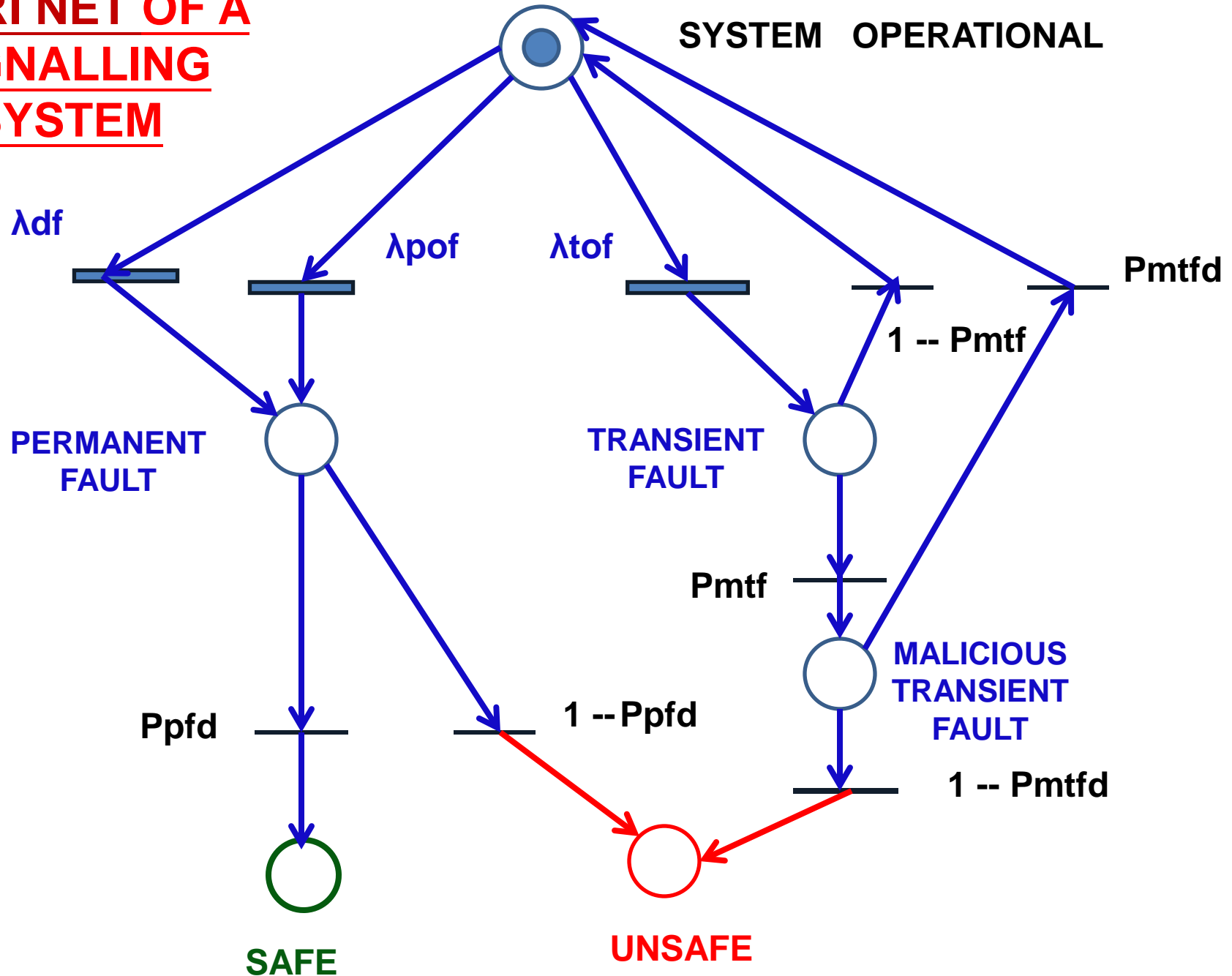
**FAILURES CAN BE DETECTED OR UNDETECTED.**

**(UNDETECTED FAILURES ARE CONSIDERED  
AS DANGEROUS).**

**PROBABILITY OF FAILURE IS GIVEN BY**

$$\begin{aligned}\lambda_{\text{SYS}} &= \lambda_{\text{SAFE}} + \lambda_{\text{DANGEROUS}} \\ &= (\lambda_{\text{SD}} + \lambda_{\text{SU}}) + (\lambda_{\text{DD}} + \lambda_{\text{DU}})\end{aligned}$$

# PETRI NET OF A SIGNALLING SYSTEM



**A PROGRAMMABLE EQUIPMENT CAN HAVE FAILURES  
DUE TO BOTH HARDWARE AND SOFTWARE.**

**IF HARDWARE FAILURE RATE =  $\lambda_H$  AND  
SOFTWARE FAILURE RATE =  $\lambda_S$**

**OVERALL UNSAFE FAILURE RATE CAN BE EXPRESSED BY**

$$\lambda_{\text{unsafe}} = (\lambda_{H\text{pof}} + \lambda_{H\text{df}} + \lambda_{S\text{pof}} + \lambda_{S\text{df}}) \cdot (1 - P_{\text{pfd}}) + (\lambda_{H\text{tof}} + \lambda_{S\text{tof}}) \cdot P_{\text{mtf}} \cdot (1 - P_{\text{mtfd}})$$

**OR**

$$\lambda_{\text{unsafe}} = (\lambda_{H\text{pof}} + \lambda_{H\text{df}}) \cdot (1 - P_{\text{pfd}}) + \lambda_{H\text{tof}} \cdot P_{\text{mtf}} \cdot (1 - P_{\text{mtfd}}) + (\lambda_{S\text{pof}} + \lambda_{S\text{df}}) \cdot (1 - P_{\text{pfd}}) + \lambda_{S\text{tof}} \cdot P_{\text{mtf}} \cdot (1 - P_{\text{mtfd}})$$

# FAILURE RATES FOR ELECTRONIC SIGNAL EQUIPMENT

ANALOG INPUT CIRCUIT FAILURE RATE =  $\lambda_{AI}$

NUMBER of ANALOG INPUT CIRCUITS =  $N_{AI}$

ANALOG OUTPUT CIRCUIT FAILURE RATE =  $\lambda_{AO}$

NUMBER of ANALOG OUTPUT CIRCUITS =  $N_{AO}$

COMMON CIRCUITRY ANALOG I/O MODULE FAILURE RATE =  $\lambda_A$

DIGITAL INPUT CIRCUIT FAILURE RATE =  $\lambda_{DI}$

NUMBER of DIGITAL INPUT CIRCUITS =  $N_{DI}$

DIGITAL OUTPUT CIRCUIT FAILURE RATE =  $\lambda_{DO}$

NUMBER of DIGITAL OUTPUT CIRCUITS =  $N_{DO}$

COMMON CIRCUITRY DIGITAL I/O MODULE FAILURE RATE =  $\lambda_D$

LOGIC SOLVER FAILURE RATE =  $\lambda_{MP}$

MODULE RACK FAILURE RATE =  $\lambda_R$

POWER SUPPLY FAILURE RATE =  $\lambda_{PS}$

## SAFE AND UNSAFE FAILURE RATES

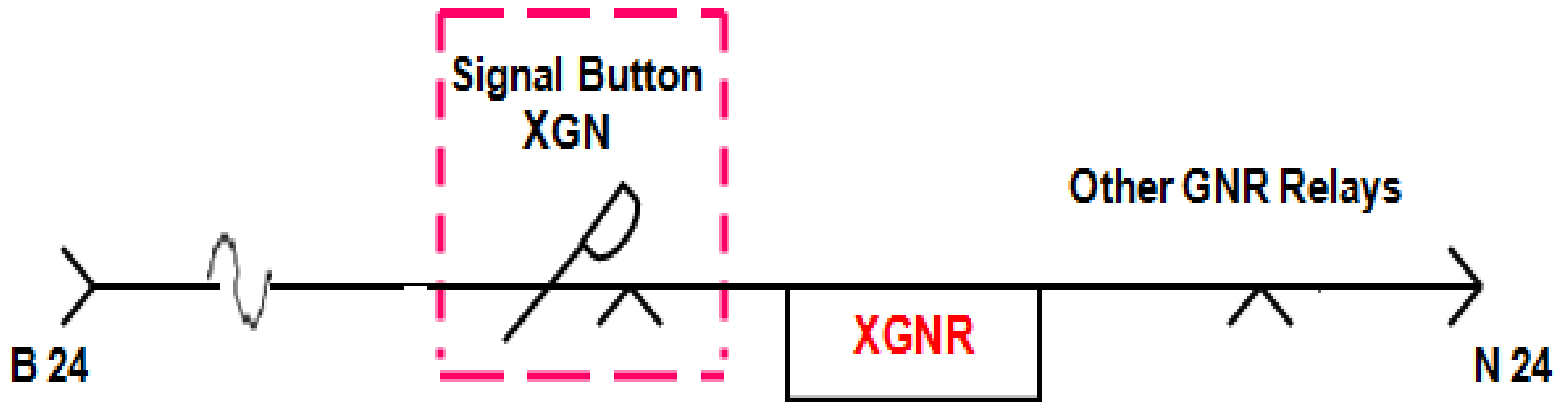
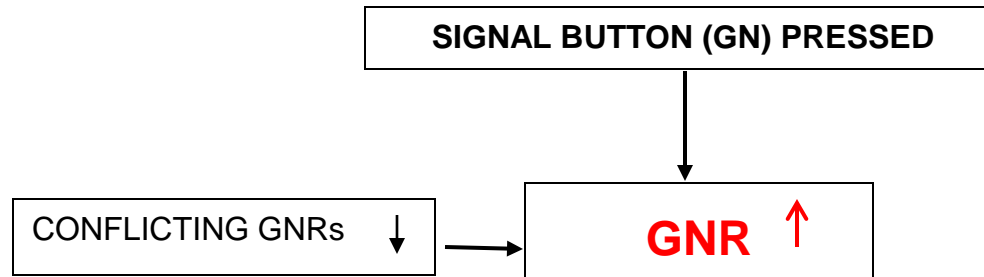
$$\lambda^{SD} = n_{DI} \lambda_{DI}^{SD} + n_{DO} \lambda_{DO}^{SD} + \lambda_D^{SD} + n_{AI} \lambda_{AI}^{SD} + n_{AO} \lambda_{AO}^{SD} + \lambda_A^{SD} + \lambda_{MP}^{SD} + \lambda_R^{SD} + \lambda_{PS}^{SD}$$

$$\lambda^{SU} = n_{DI} \lambda_{DI}^{SU} + n_{DO} \lambda_{DO}^{SU} + \lambda_D^{SU} + n_{AI} \lambda_{AI}^{SU} + n_{AO} \lambda_{AO}^{SU} + \lambda_A^{SU} + \lambda_{MP}^{SU} + \lambda_R^{SU} + \lambda_{PS}^{SU}$$

$$\lambda^{DD} = n_{DI} \lambda_{DI}^{DD} + n_{DO} \lambda_{DO}^{DD} + \lambda_D^{DD} + n_{AI} \lambda_{AI}^{DD} + n_{AO} \lambda_{AO}^{DD} + \lambda_A^{DD} + \lambda_{MP}^{DD} + \lambda_R^{DD} + \lambda_{PS}^{DD}$$

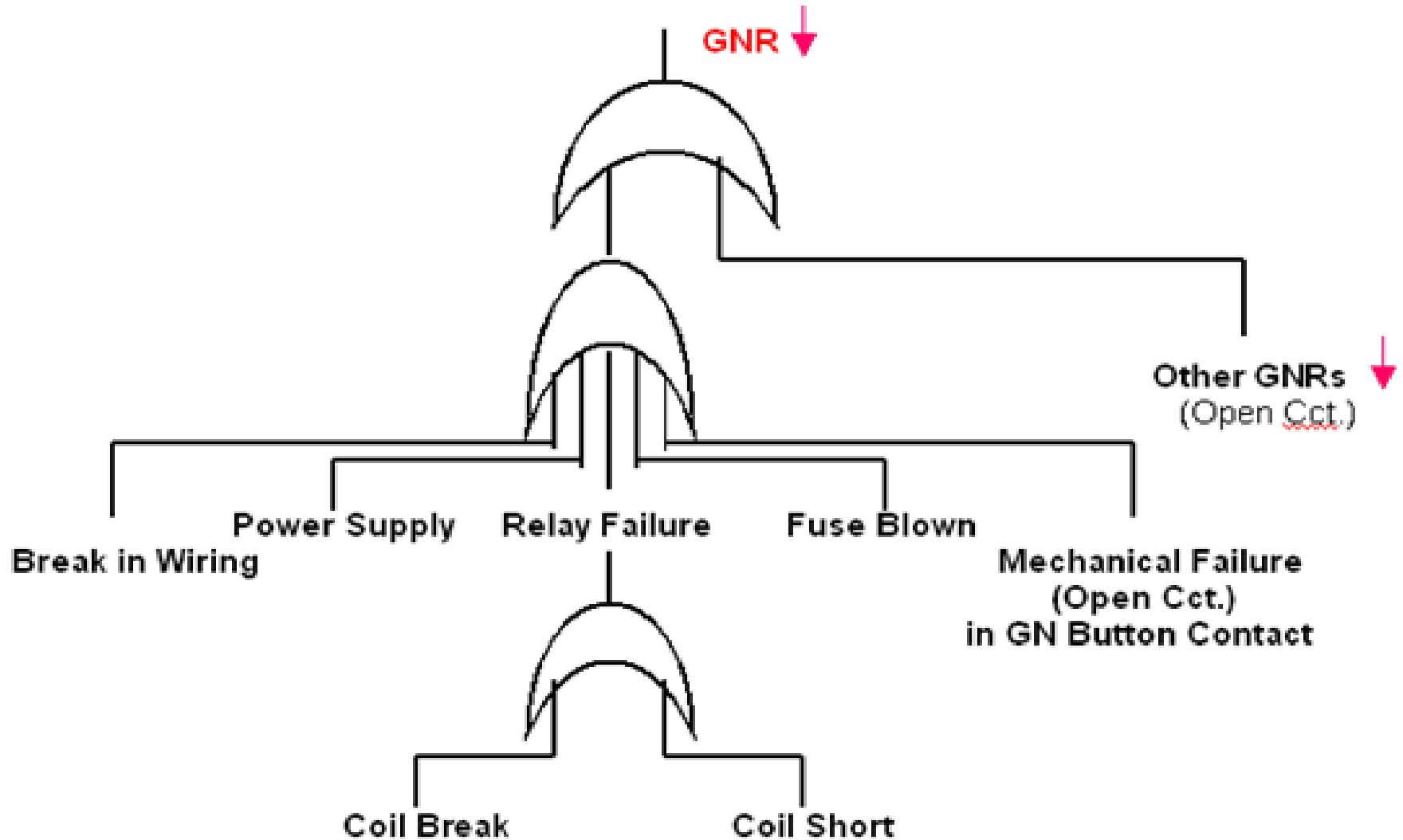
$$\lambda^{DU} = n_{DI} \lambda_{DI}^{DU} + n_{DO} \lambda_{DO}^{DU} + \lambda_D^{DU} + n_{AI} \lambda_{AI}^{DU} + n_{AO} \lambda_{AO}^{DU} + \lambda_A^{DU} + \lambda_{MP}^{DU} + \lambda_R^{DU} + \lambda_{PS}^{DU}$$

# SIGNAL BUTTON CIRCUIT IN RELAY INTERLOCKING





# FAULT TREE FOR SAFE FAILURE OF SIGNAL BUTTON RELAY (GNR) OF BRITISH ROUTE RELAY INTERLOCKING



$$\lambda_{\text{safe}} = \lambda_{\text{GNR}} + \lambda_{\text{FUSE}} + \lambda_{\text{POWER}} + \lambda_{\text{WIRING}} + \lambda_{\text{CONTACT. FLT (Button)}} + \lambda_{\text{Other GNRs (13)}}$$

**AS PER RAILTRACK IRM CCA MODEL,**

$$\lambda_{\text{RELAY (open)}} = 0.7495 \times 10^{-6} / \text{Hr.},$$

$$\lambda_{\text{RELAY (short)}} = 0.4307 \times 10^{-6} / \text{Hr}$$

$$\lambda_{\text{WIRING (Open)}} = 6.554 \times 10^{-8} / \text{Hr.},$$

$$\lambda_{\text{FUSE}} = 0.04 \times 10^{-6} / \text{Hr.},$$

$$\lambda_{\text{POWER}} = 0.04 \times 10^{-6} / \text{Hr.}$$

**AND AS PER MIL STD. 217F (CONSIDERING 5 OPERATIONS / HR.),**

$$\lambda_{\text{CONTACT FLT}} = 0.3468 \times 10^{-6} / \text{Hr. (for GN Button)}$$

**REPLACING THESE VALUES IN THE EQUATION,**

$$\lambda_{\text{safe}} = (0.7495 \times 10^{-6} + 0.4307 \times 10^{-6} + 6.554 \times 10^{-8} + 2 \times 0.04 \times 10^{-6} + 0.3468 \times 10^{-6} + 13 \times 0.7495 \times 10^{-6}) / \text{Hr} = \underline{\underline{11.416 \times 10^{-6} / \text{Hr.}}}$$

# FAILURE RATE FOR RESISTORS USED IN AXLE COUNTER AS PER MIL 217F ITEM 9.1)

$$\lambda_B = 4.5 \times 10^{-9} \exp \left( \frac{12 (T + 273)}{343} \right) \exp \left( \frac{S}{0.6} \right) \exp \left( \frac{(T + 273)}{273} \right)$$

LET US TAKE AN EXAMPLE – A RESISTOR OF VALUE 2.2 K $\Omega$  OF  
**LOW QUALITY** WORKING AT **45 °C** WILL HAVE

$$\begin{aligned} \lambda_B &= 4.5 \times 10^{-9} \exp \left( \frac{12 (45 + 273)}{343} \right) \exp \left( \left( \frac{0.1}{0.6} \right) \times \frac{(45 + 273)}{273} \right) \\ &= 4.5 \times 10^{-9} \exp \left( \frac{12 \times (318)}{343} \right) \exp \left( \frac{0.1666 \times (318)}{273} \right) \\ &= 4.5 \times 10^{-9} \exp (12 \times 0.92711) \exp (0.1666 \times 1.16483) \\ &= 4.5 \times 10^{-9} \exp^{11.12536} \exp^{0.19406} \\ &= 4.5 \times 10^{-9} \times 67870.72 \times 1.21417 \\ &= 370829.399 \times 10^{-9} = \underline{\underline{0.00037 / 10^6 \text{ Hrs.}}} \end{aligned}$$

THE **MODIFIED FAILURE RATE (UNDER STRESS)** OF THE RESISTOR

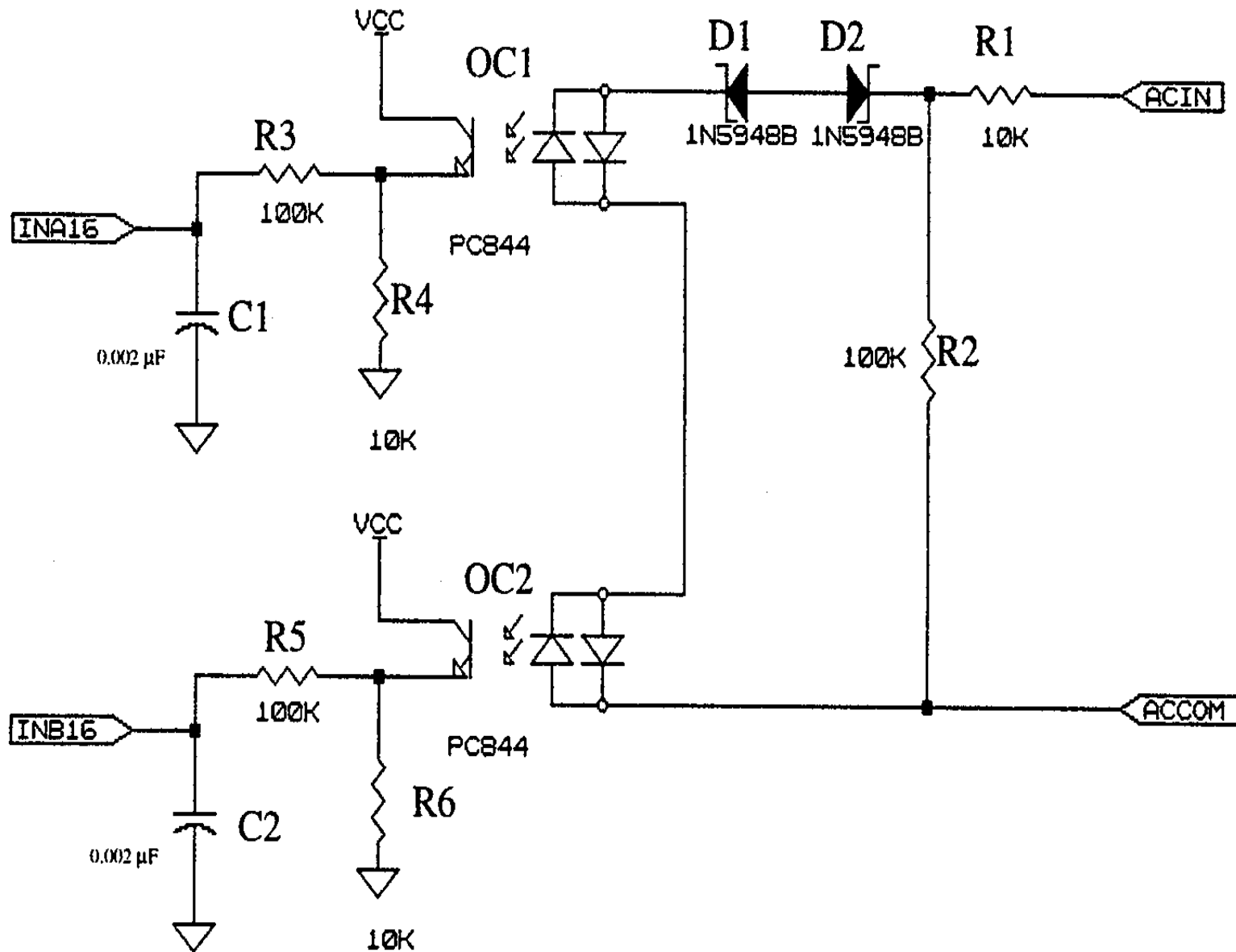
$$\lambda_P = \lambda_B \times \Pi_Q \times \Pi_E \times \Pi_R = 0.00037 \times 15 \times 3 \times 1 = \underline{\underline{0.016687/10^6 \text{ Hrs.}}}$$

## EFFECT OF AMBIENT TEMPERATURE AND COMPONENT QUALITY (AMPL.– RECT.CARD OF CEL AXLE COUNTER)

Part Description	$\lambda_p$ at 45°C	$\lambda_p$ at 30°C	$\lambda_p$ at 30°C and better Quality Parts	Contribution percentage
Capacitors	3.120181	2.0211954	0.4937654	38.33 %
Resistors	3.5059	2.38384	1.01048	43.07 %
Semiconductors	0.25688	0.25688	0.112088	3.15 %
Transformers & Coil	1.023	0.8884	0.34558	12.5 %
Connectors	0.16747	0.11847	0.0389	2.05 %
Reflow Connections	0.06541			0.8 %
<b>TOTAL</b>	<b>8.13884</b>	<b>5.73419</b>	<b>1.62183</b>	

**CHANGE IN AMBIENT TEMPERATURE IMPROVES FAILURE RATE BY 29.5% AND CHANGE IN COMPONENT QUALITY , ALONG WITH TEMPERATURE, BY 80%**

# FMECA OF AN INPUT INTERFACE CIRCUIT



### Failure Modes, Effects and Diagnostic Analysis

1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		
Name	Code	Function	Mode	Cause	Effect	Criticality $\lambda$		Remarks	Det.	Diagnostics	Mode	SD	SU	DD	DU		
R1-10K	4555-10	Input threshold	short		Threshold shift	Safe	0.125		0			1	0	0.13	0	0	
			open	solder open	open circuit	Safe	0.5		1	lose input pulse		1	0.5	0	0	0	
			drift low			Safe	0.01	none until too low		0			1	0	0.01	0	0
			drift high			Safe	0.01	none until too high		1	lose input pulse		1	0.01	0	0	0
R2100K	4555-100	current limit	short		short input	Safe	0.125		1			1	0.13	0	0	0	
			open	solder open		Safe	0.5		1	lose input pulse			0	0	0.5	0	
			drift low			Safe	0.01	none until too low		0			1	0	0.01	0	0
			drift high			Safe	0.01	none until too high		1	lose input pulse		1	0.01	0	0	0
D1	4200-7	voltage drop	short	surge	overvoltage	Safe	2		1	lose input pulse		1	2	0	0	0	
			open		open circuit	Safe	5		1	lose input pulse		1	5	0	0	0	
D2	4200-7	voltage drop	short	surge	overvoltage	Safe	2		1	lose input pulse		1	2	0	0	0	
			open		open circuit	Safe	5		1	lose input pulse		1	5	0	0	0	
OC1	4805-25	isolate	led dim	wear	no light	Safe	28		1	Comp. mismatch		1	28	0	0	0	
			tran. short	internal short	read logic 1	Dang.	10		1	Comp. mismatch		0	0	0	10	0	
			tran. open		read logic 0	Safe	6		1	Comp. mismatch		1	6	0	0	0	
OC2	4805-25	isolate	led dim	wear	no light	Safe	28		1	Comp. mismatch		1	28	0	0	0	
			tran. short	internal short	read logic 1	Dang.	10		1	Comp. mismatch		0	0	0	10	0	
			tran. open		read logic 0	Safe	6		1	Comp. mismatch		1	6	0	0	0	
OC1/OC2			cross channel short		same signal	Dang.	0.01		0			0	0	0	0.01		

R3-100K	4555-100	filter	short	lose filter	Safe	0.125	0	1	0	0.13	0	0
			open	input float high	Dang.	0.5	1	0	0	0	0.5	0
R4-10K	4555-10	voltage divider	short	read logic 0	Safe	0.125	1	1	0.13	0	0	0
			open	read logic 1	Dang.	0.5	1	0	0	0	0.5	0
R5-100K	4555-100	filter	short	lose filter	Safe	0.125	0	1	0	0.13	0	0
			open	input float high	Dang.	0.5	1	0	0	0	0.5	0
R6-10K	4555-10	voltage divider	short	read logic 0	Safe	0.125	1	1	0.13	0	0	0
			open	read logic 1	Dang.	0.5	1	0	0	0	0.5	0
C1	4350-32	filter	short	read logic 0	Safe	2	1	1	2	0	0	0
C2	4350-32	filter	open	lose filter	Safe	0.5	0	1	0	0.5	0	0
			short	read logic 0	Safe	2	1	1	2	0	0	0
			open	lose filter	Safe	0.5	0	1	0	0.5	0	0
						110.8			86.9	1.4	22.5	0.01

Total Failure Rate 110.8 Safe Coverage 0.9839

Total Safe Failure Rate 88.29 Dang. Coverage 0.9996

Total Dangerous Failure Rate 22.51

Safe Detected Failure Rate 86.895

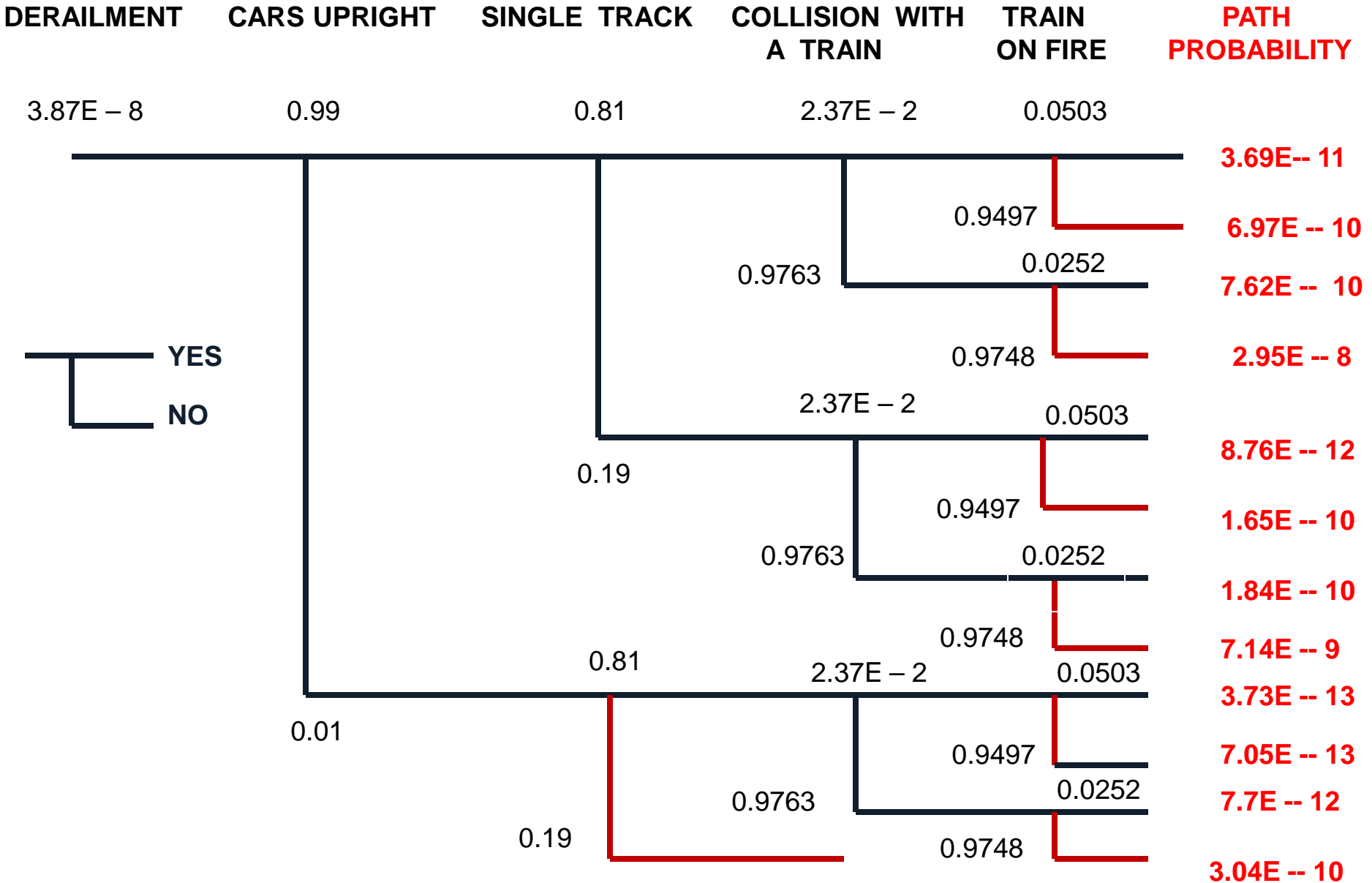
Safe Undetected Failure Rate 1.395

Dangerous Detected Failure Rate 22.5

Dangerous Undetected Failure Rate 0.01

Failures per Billion Hours

# EVENT TREE ANALYSIS





**HAZARD PROBABILITY**

**0.9917**

**0.00425**

**0.00425**

**SAFE CONDITION**

**ACCIDENT**

**NEAR MISS**

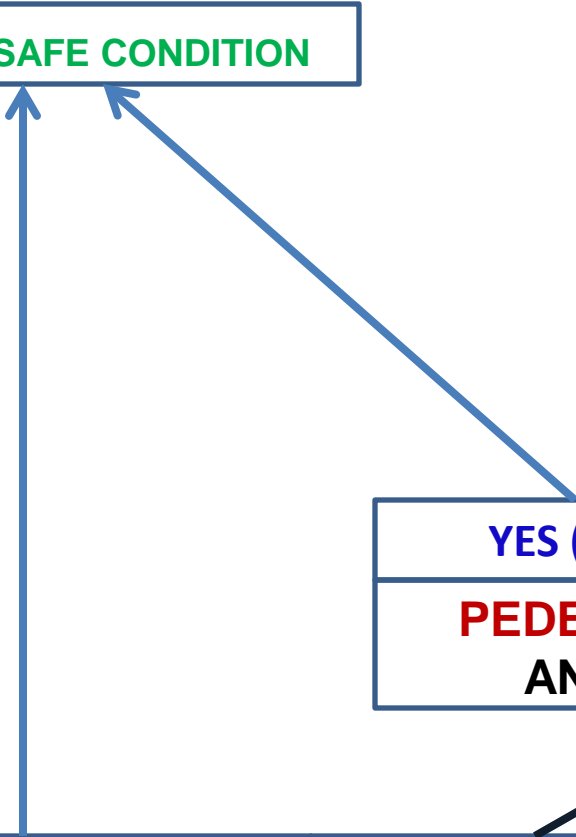
**CONSEQUENCE ANALYSIS**

<b>YES (0.5)</b>	<b>NO (0.5)</b>
<b>PEDESTRIAN HIT BY TRAIN</b>	

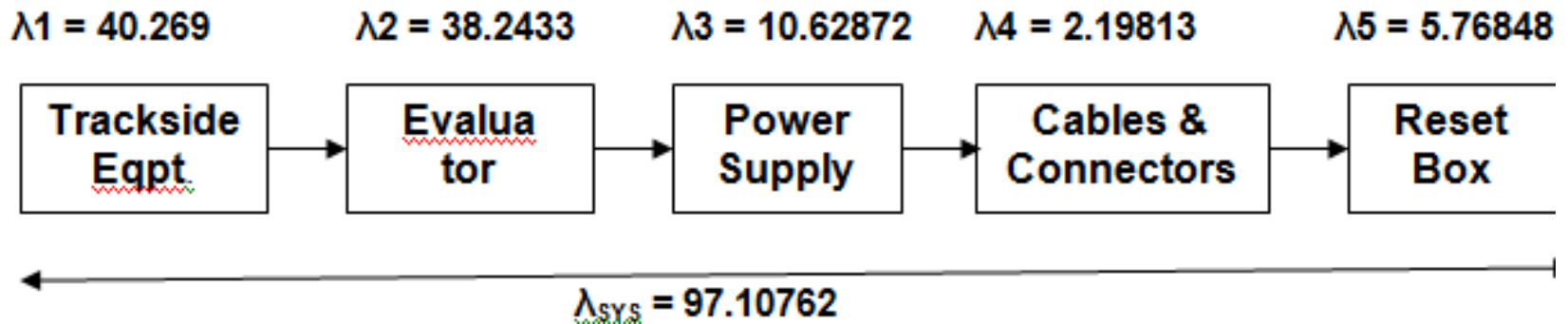
<b>YES (0.9)</b>	<b>NO (0.1)</b>
<b>PEDESTRIAN NOTICES TRAIN AND TAKES ACTION</b>	

<b>NO (0.917)</b>	<b>YES (0.083)</b>
<b>PEDESTRIAN AT LEVEL CROSSING</b>	

**FAILURE OF LEVEL CROSSING GATE TO PROTECT PUBLIC FROM TRAIN**



# RELIABILITY BLOCK DIAGRAM OF UNIVERSAL AXLE COUNTER.



CALCULATING INDIVIDUAL RELIABILITY VALUES, WE FIND

$$R_1 = 0.99995963, R_2 = 0.9999617, R_3 = 0.9999894, \\ R_4 = 0.9999978 \text{ AND } R_5 = 0.9999942$$

$$R_{SYS} = R_1 \times R_2 \times R_3 \times R_4 \times R_5$$

$$= (0.99995963 \times 0.9999617 \times 0.9999894 \times 0.9999978 \times 0.9999942) \\ = 0.999902865$$

SEPARATELY CALCULATING  $R_{SYS}$  FROM  $\lambda_{SYS}$  THE VALUE IS 0.999902897

# FAILURE RATE OF A TYPICAL ELECTRONIC INTERLOCKING EQPT.

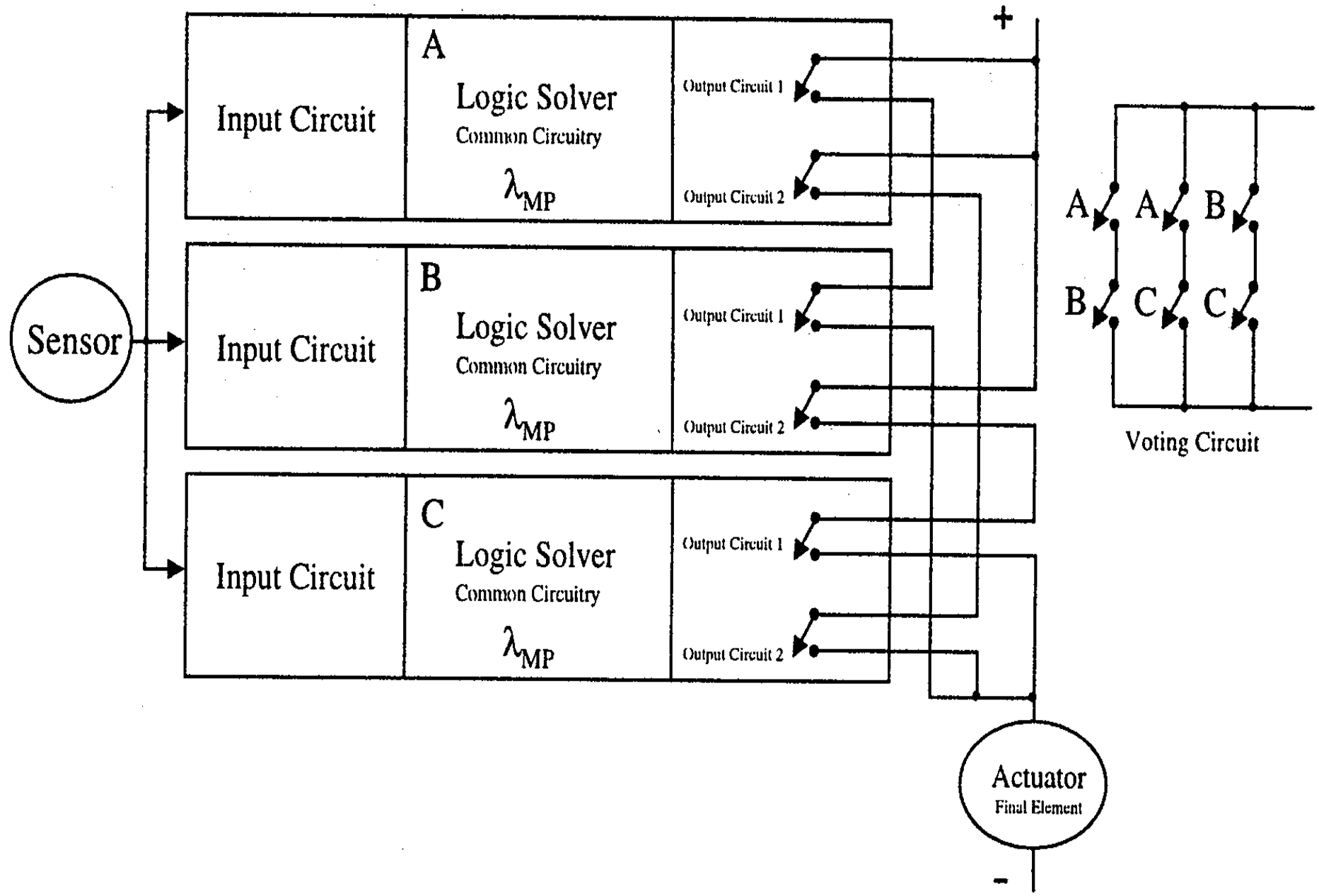
<u>SUB-SYSTEM NAME</u>	<u>QTY</u>	<u>FAULTS/10<sup>6</sup> Hr</u>	<u>TOTAL FAULTS/10<sup>6</sup> Hr</u>
PROCESSOR BOARD	1	2.14470	<b>2.1447</b>
I/O BUS INTERFACE BOARD	1	2.8679	<b>2.8679</b>
CODE SYSTEM INTERFACE BOARD	1	2.9182	<b>2.9182</b>
PERIPHERAL BOARD	1	2.1412	<b>2.1412</b>
CPU POWER SUPPLY	1	1.5545	<b>1.5545</b>
12V INPUT BOARD	7	1.2741	<b>8.9187</b>
RELAY DRIVER BOARD	7	0.7102	<b>4.9714</b>
I/O POWER SUPPLY	1	0.8234	<b>0.8234</b>
<b>TOTAL</b>			<b>26.34</b>

**BUT RELIABILITY IS REDUCED WITH TIME !**

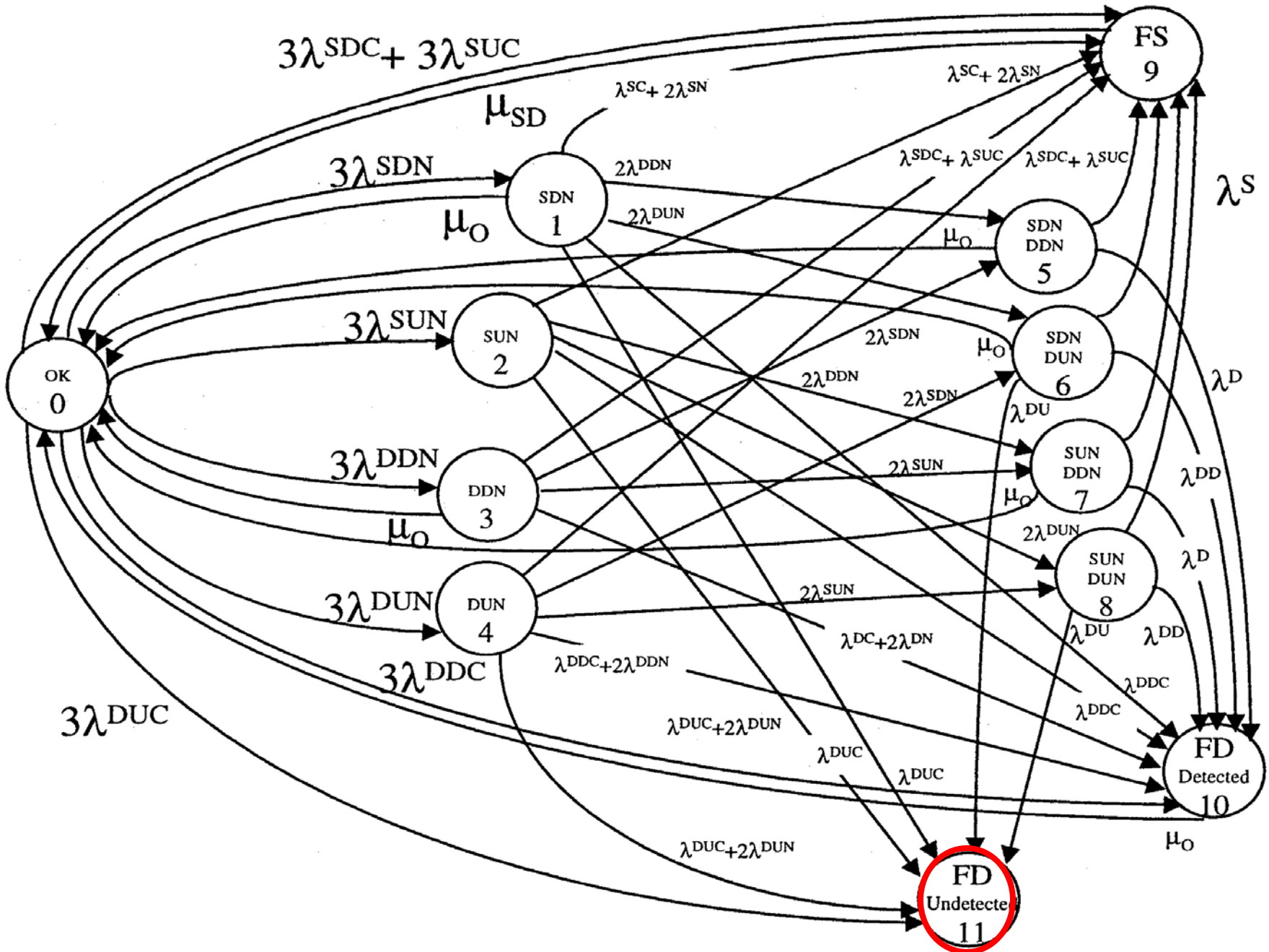
<b>Const. Failure Rate / Hr</b>	<b>After 1 Year</b>	<b>After 2 Years</b>	<b>After 3 Years</b>	<b>After 4 Years</b>	<b>After 5Years</b>
<b>3 /10<sup>7</sup> Hrs</b>	<b>99.7375%</b>	<b>99.4758%</b>	<b>99.2147%</b>	<b>98.9543%</b>	<b>98.6946%</b>
<b>3 /10<sup>8</sup> Hrs</b>	<b>99.9723%</b>	<b>99.9474%</b>	<b>99.9212%</b>	<b>99.8949%</b>	<b>99.8687%</b>

**RELIABILITY AT THE END OF LIFE MUST BE USED TO DETERMINE THE INITIAL RELIABILITY.**

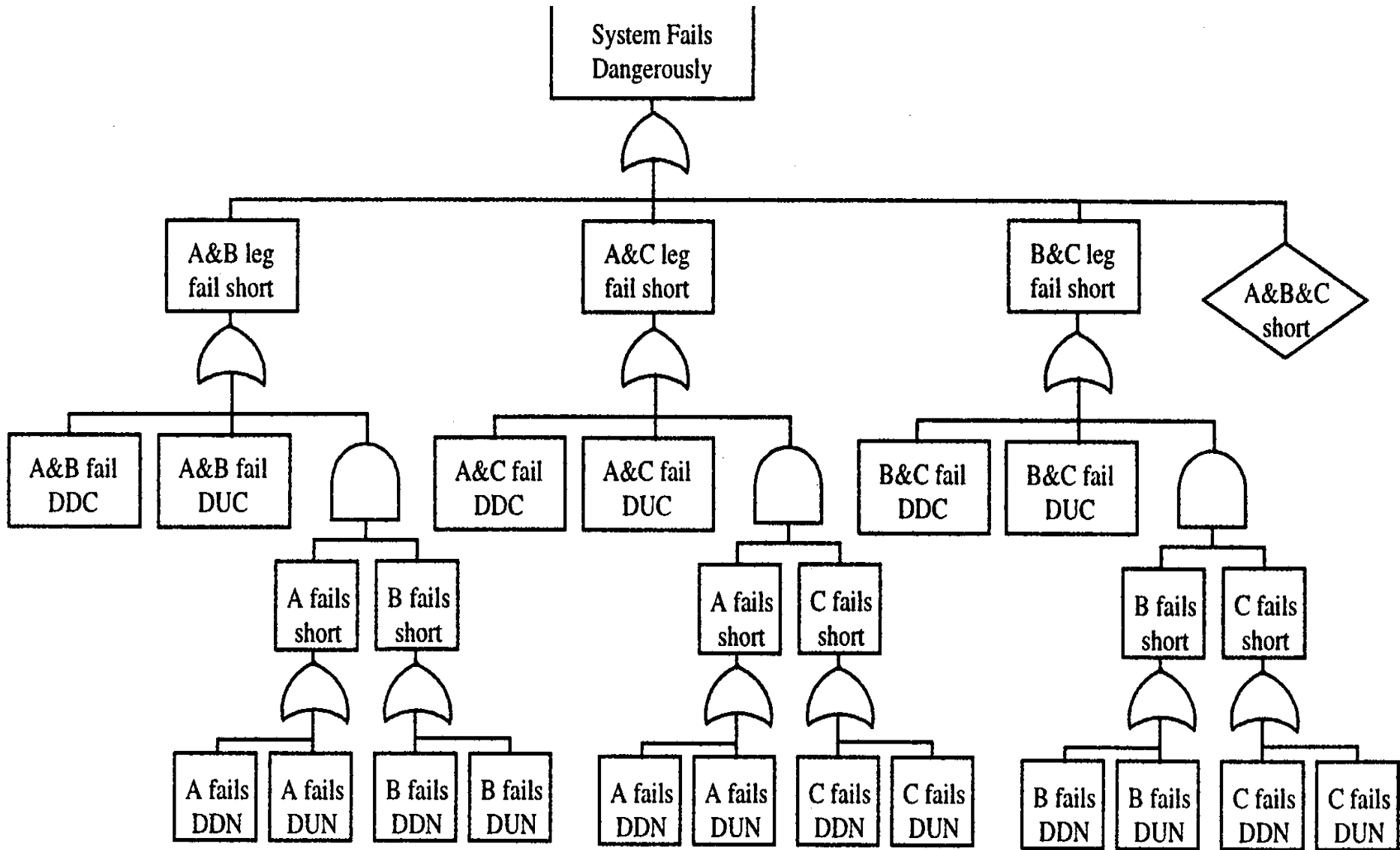
# 2oo3 ARCHITECTURE



# 2003 ARCHITECTURE MARKOV DIAGRAM



# PFD FAULT TREE FOR 2oo3 SYSTEM



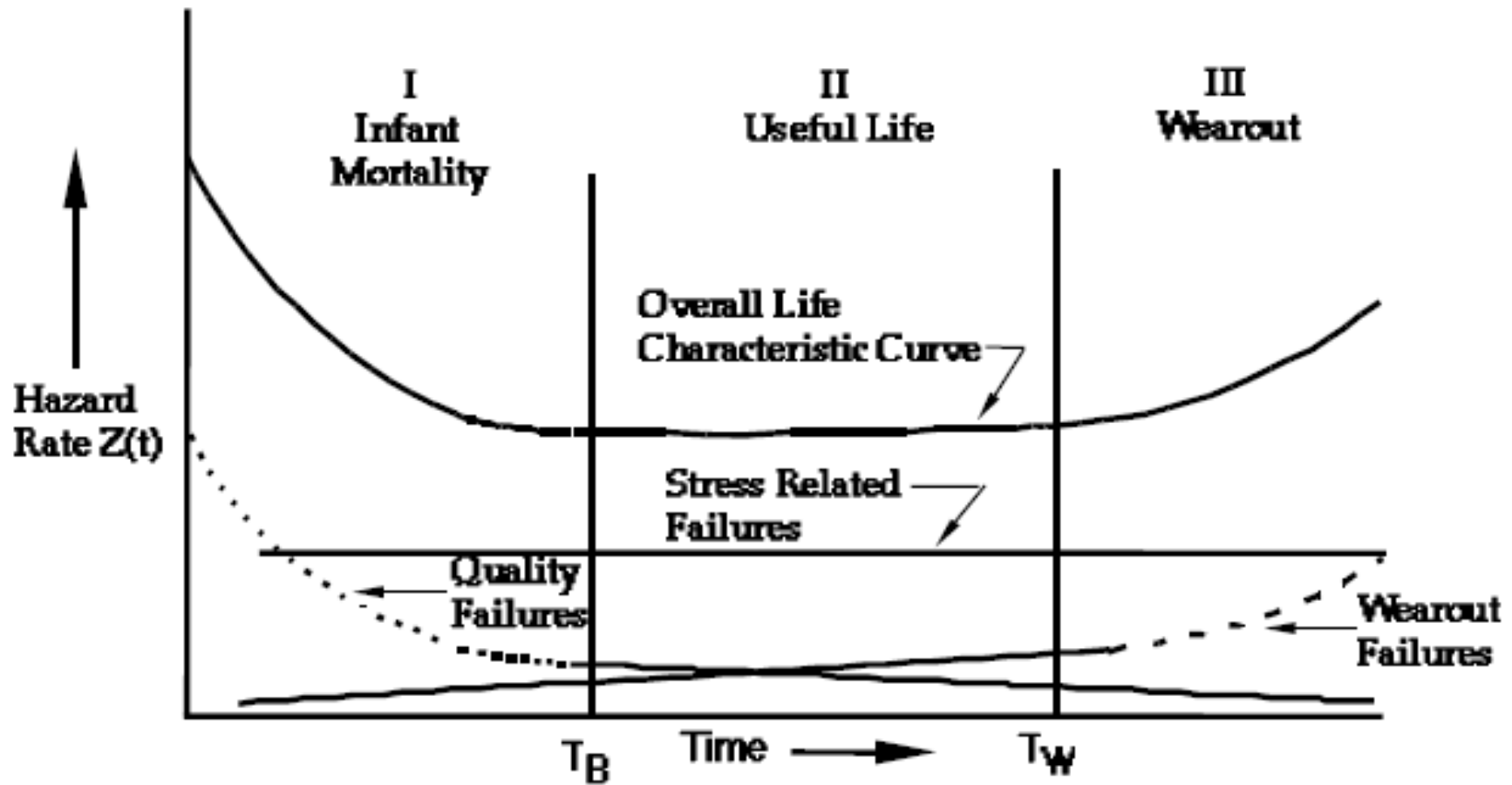
$$\begin{aligned}
 \text{PFD}_{\text{avg}2\text{oo}3} = & 3\lambda^{\text{DUC}} * \text{TI} / 2 + 3\lambda^{\text{DDC}} * \text{RT} + 3[(\lambda^{\text{DDN}} * \text{RT})^2 + (\lambda^{\text{DDN}} * \text{RT} * \lambda^{\text{DUN}} * \text{TI}) / 2 \\
 & + (\lambda^{\text{DUN}} * \text{TI})^2 / 3]
 \end{aligned}$$

# COMPARISON BETWEEN ANALYSIS TECHNIQUES

ANALYSIS TECHNIQUES	FMECA	RBD	FTA	HYBRID TECHNIQUE	MARKOV MODEL
<b>ASPECTS COVERED</b>					
<b>EFFECTS OF REDUNDANCY</b>		√	√	√	√
<b>COMMON CAUSE FAILURES</b>		√	√	√	√
<b>SYSTEMATIC FAILURES</b>	√	√	√		√
<b>EFFECTS OF DIAGNOSTICS</b>	√		√	√	√
<b>EFFECTS OF TEST &amp; REPAIR</b>			√	√	√
<b>TIME / SEQUENCE DEPENDENT ASPECTS</b>					√



# BATH TUB CURVE (HAZARD RATE vs TIME)



$T_B$  = possible burn-in time     $T_W$  = wear begins

# IMPROVEMENT IN LIFE-TIME RESULTING FROM AN INITIAL BURN-IN PERIOD

LET A COMPONENT FOR AXLE COUNTER CARD HAVE A DECREASING FAILURE RATE OF  $\lambda T = 0.0005 (T / 1000)^{-0.5}$  / YEAR. FIND THE INFLUENCE OF A BURN-IN PERIOD OF 6 MONTHS ON THE LIFE-TIME OF THE COMPONENT, CONSIDERING RELIABILITY OF 0.9.

Answer:  $R_{(t)} = 0.9$ , i.e.  $\exp [-(t / 1000)^{-0.5}] = 0.9$  FROM THIS,

$$t = 1000 \{-\ln (0.9)\}^2 = 1000 \times (0.10536)^2 = 1000 \times 0.0111 = 11.1 \text{ Yrs}$$

WHEN A BURN-IN PERIOD OF 6 MONTHS (0.5 YR) IS INTRODUCED,

$$R_{(t|T)} = 0.9, \text{ i.e.}$$

$$\exp [-(t + 0.5 / 1000)^{-0.5}] / \exp [-(0.5 / 1000)^{-0.5}] = 0.9$$

$$\begin{aligned} t &= 1000 \{-\ln 0.9 + (0.5 / 1000)^{-0.5}\}^2 - 0.5 = 1000 \{0.10536 + 0.02236\}^2 - 0.5 \\ &= 1000 \{0.12772\}^2 - 0.5 = (1000 \times 0.1631) - 0.5 = 16.31 - 0.5 \\ &= 15.81 \text{ Yrs} \end{aligned}$$

AN INCREASE OF 4.71 YRS IN THE DESIGNED LIFE OF THE COMPONENT.

# SPARE PARTS CALCULATION

LET  $\lambda = 1 \times 10^{-5}$  / hr. BE THE **CONSTANT FAILURE RATE OF A VITAL SPARE PART IN A SYSTEM. THERE ARE 6 SYSTEMS INSTALLED AND A CUMULATIVE OPERATING TIME OF 50,000 HRS FOR EACH SYSTEM IS NEEDED. DESIRED SYSTEM RELIABILITY IS  $\geq 0.99$ . HOW MANY SPARE PARTS ARE NEEDED?**

ANSWER:

FOR CENTRALIZED STORE

NO. OF FAILURES =  $50000 / 100000 = 0.5 \approx 1$  AND **RELIABILITY = 0.99**

FOR THIS VALUE,  **$d = 2.33$**  (FROM STANDARD NORMAL DISTRIBUTION TABLE) AND  **$kd/2 = 1.165$** , as  **$k$  (COEFFICIENT of DISTRIBUTION) = 1**

Now  **$K T \lambda = 6 \times 50000 \times 0.00001 = 3$** , where  $K$  = No. of SYSTEMS

$$\begin{aligned} \text{So, } n &= [kd/2 + \{(kd/2)^2 + K T \lambda\}^{1/2}]^2 \\ &= [1.165 + \{(1.165)^2 + 3\}^{1/2}]^2 \\ &= [1.165 + 2.0874]^2 = (3.2524)^2 = 10.57 \approx 11 \end{aligned}$$

## FOR DECENTRALIZED STORE

NO. OF FAILURES = 50000 / 100000 = 0.5  $\approx$  1  
**INDIVIDUAL RELIABILITY** AT EACH SYSTEM IS  
 $(0.99)^{1/6} = \mathbf{0.99888}$

FOR THIS VALUE, **d = 2.99**  
(FROM **STANDARD NORMAL DISTRIBUTION Table**)  
AND **kd/2 = 1.495**

NOW  $KT\lambda = 50000 \times 0.00001 = 0.5$

$$\begin{aligned} \text{So, } n &= [kd/2 + \{(kd/2)^2 + KT\lambda\}^{1/2}]^2 \\ &= [1.495 + \{(1.495)^2 + 0.5\}^{1/2}]^2 \\ &= [1.495 + 1.6538]^2 \\ &= (3.783)^2 = 9.915 \approx \mathbf{10} \end{aligned}$$

FOR THE SYSTEM HAVING **SIX EQUIPMENT**,  
**TOTAL SPARES NEEDED** WILL BE **60**.

**SO, DECENTRALIZED STORES NEED MUCH MORE SPARES.**

# ADEQUACY OF SPARE PARTS

SUPPOSE A COMPONENT IN A SIGNALLING EQUIPMENT HAS A FATIGUE RATE OF 0.000003/ Hr. SIGNAL REPAIR SHOP HAS PROCURED TWO SPARE COMPONENTS. IF THE DESIGN LIFE OF THE EQUIPMENT IS 20 Yrs, WHAT IS THE PROBABILITY THAT SPARES WILL BE ADEQUATE FOR 10 SUCH EQUIPMENT?

## ANSWER

EXPECTED FAILURES DURING EQUIPMENT LIFE IS

$$= 10 \times 3 \times 10^{-6} \times 20 \times 8760 = 5.256.$$

PROBABILITY OF  $\leq 2$  FAILURES IN 20 Yrs,

$$\begin{aligned} R_{(20)} &= \sum_{n=0}^2 \{ e^{-5.256} (5.256)^n / n! \} \\ &= e^{-5.256} \{ (5.256)^0 / 0! + (5.256)^1 / 1! + (5.256)^2 / 2! \} \\ &= 0.005216 \{ 1 + 5.256 + 13.812768 \} \\ &= 0.005216 \times 20.068768 \\ &= 0.1046787 \end{aligned}$$

# INFLUENCE OF PERIODICAL INSPECTION ON AVAILABILITY

LET US CONSIDER A UNIVERSAL AXLE COUNTER EQUIPMENT HAVING  
A **CONSTANT FAILURE RATE OF 0.0000971 FAILURE/ 10<sup>6</sup> HRS.**

ANY DEFECTIVE COMPONENT WOULD BE REPLACED / REPAIRED, IF  
FOUND DEFECTIVE DURING THE PERIODIC INSPECTION.

THE INSPECTION TIME IS 1 HR AND REPAIR / REPLACEMENT  
TAKES 8 HRS (WORST CASE).

WHAT IS THE **OPTIMUM TIME BETWEEN INSPECTIONS?**

ANSWER:

WE USE THE FORMULA  $A_{(T)} = (1 - e^{-\lambda T}) / \lambda [T + t_1 + t_2 (1 - e^{-\lambda T})]$

WHERE,

$\lambda = 0.0000971$ ,  $t_1 = 1$  hr,  $t_2 = 8$  hr and  $T =$  INSPECTION PERIODICITY.

LET US CONSIDER **168 HRS, 336 HRS, 504 HRS AND 672 HRS** AS THE  
INSPECTION INTERVALS AND FIND AVAILABILITY AT THESE PERIODS.

$$\begin{aligned}
A_{(168)} &= (1 - e^{-0.0000971 \times 168}) / [0.0000971 \{168 + 1 + 8(1 - e^{-0.0000971 \times 168})\}] \\
&= (1 - e^{-0.0163128}) / [0.0000971 \{169 + 8(1 - e^{-0.0163128})\}] \\
&= (1 - 0.98388195) / [0.0000971 \{169 + 8(1 - 0.98388195)\}] \\
&= 0.0161804 / [0.0000971 \{169 + 8 \times (0.0161804)\}] \\
&= 0.0161804 / [0.0000971 \times 169.1294432] = 0.0161804 / 0.01642247 \\
&= \mathbf{0.9852598}
\end{aligned}$$

BY SIMILAR CALCULATIONS, WE FIND THE VALUES:

$$A_{(336)} = \mathbf{0.9801959}, A_{(504)} = \mathbf{0.9732559}, A_{(672)} = \mathbf{0.9662714}$$

**MAXIMUM AVAILABILITY IS FOR AN INSPECTION INTERVAL OF 168 HRS.**

WE NOW CONSIDER INSPECTION PERIODICITY OF **96 HRS AND 240 HRS.**

$$A_{(96)} = \mathbf{0.98434} \text{ AND } A_{(240)} = \mathbf{0.983582}$$

	96	168	240	336	504	672
T (Hr)	96	168	240	336	504	672
$A_{(T)}$	0.98434	0.9852598	.983582	.9801959	0.9732559	0.9662714

# EXAMPLE OF QUANTIFICATION OF SOFTWARE TESTING

<b>TOTAL STATEMENTS</b>	<b>= 10</b>
<b>NESTED LEVEL</b>	<b>= 4</b>
<b>TOTAL LINES</b>	<b>= 79</b>
<b>SOURCE ONLY LINES</b>	<b>= 21</b>
<b>SOURCE &amp; COMMENTS LINES</b>	<b>= 0</b>
<b>COMMENTS ONLY LINES</b>	<b>= 55</b>
<b>EMPTY LINES</b>	<b>= 3</b>
<b>COMMENTS LINES RATE</b>	<b>= 69.62%</b>



## SOME SAFETY QUANTIFICATION PARAMETERS

<b>FAILURE RATE</b>	<b>= <math>10^{-6}/\text{Hr}</math></b>
<b>SAFE FAILURE RATIO</b>	<b>&gt; 0.99</b>
<b>DIAGNOSTIC COVERAGE FACTOR</b>	<b>= 0.99</b>
<b>COMMON CAUSE (<math>\beta</math>) FACTOR</b>	<b>= 0.05</b>
<b>REPAIR TIME</b>	<b>= 4 Hrs. TO 1 DAY</b>
<b>PROOF TEST TIME</b>	<b>= 0.25 TO 1 YEAR</b>
<b>PROOF TEST COVERAGE FACTOR</b>	<b>= 0.8</b>
<b>TIME TO COMPLETE OVERHAUL</b>	<b>= 4 TO 6 YEARS</b>

# TRAINING MODULES IN QUANTITATIVE TECHNIQUES

**FAULT TREE ANALYSIS.**

**FMECA AND FAULT INJECTION TECHNIQUES.**

**MARKOV DIAGRAM AND ANALYSIS.**

**RELIABILITY BLOCK DIAGRAMS.**

**HAZARD IDENTIFICATION AND RANKING.**

**SAFETY INTEGRITY LEVEL CALCULATION.**

**CAUSAL & CONSEQUENCE ANALYSIS.**

**LOSS, OPTIONS & IMPACT ANALYSIS.**

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**σας ευχαριστώ**

**GRACIAS !**

**TACK !**